Infineon Technologies - XC2234L20F66LAAKXUMA1 Datasheet

Welcome to E-XFL.COM

What is "Embedded - Microcontrollers"?

"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "Embedded - Microcontrollers"

Details	
Product Status	Obsolete
Core Processor	C166SV2
Core Size	16/32-Bit
Speed	66MHz
Connectivity	CANbus, I²C, LINbus, SPI, SSC, UART/USART, USI
Peripherals	I²S, POR, PWM, WDT
Number of I/O	48
Program Memory Size	160KB (160K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	10K x 8
Voltage - Supply (Vcc/Vdd)	3V ~ 5.5V
Data Converters	A/D 19x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 125°C (TA)
Mounting Type	Surface Mount
Package / Case	64-LQFP Exposed Pad
Supplier Device Package	PG-LQFP-64-22
Purchase URL	https://www.e-xfl.com/product-detail/infineon-technologies/xc2234l20f66laakxuma1

16/32-Bit

Architecture

XC2230L, XC2234L

16/32-Bit Single-Chip Microcontroller
with 32-Bit Performance
XC2000 Family / Econo Line

Data Sheet

V1.3 2015-02

Microcontrollers

- On-Chip Peripheral Modules
  - Synchronizable 12-bit A/D Converter with up to 19 channels, conversion time below 1 µs, optional data preprocessing (data reduction, range check), broken wire detection
  - 16-channel general purpose capture/compare unit (CC2)
  - Two capture/compare units for flexible PWM signal generation (CCU6x)
  - Multi-functional general purpose timer unit with 5 timers
  - Up to 4 serial interface channels to be used as UART, LIN, high-speed synchronous channel (SPI/QSPI), IIC bus interface (10-bit addressing, 400 kbit/s), IIS interface
  - On-chip MultiCAN interface (Rev. 2.0B active) with up to 32 message objects (Full CAN/Basic CAN) on 2 CAN nodes and gateway functionality
  - On-chip system timer and on-chip real time clock
- Single power supply from 3.0 V to 5.5 V
- Power reduction and wake-up modes with flexible power management
- Programmable window watchdog timer and oscillator watchdog
- Up to 48 general purpose I/O lines
- On-chip bootstrap loaders
- Supported by a full range of development tools including C compilers, macro-assembler packages, emulators, evaluation boards, HLL debuggers, simulators, logic analyzer disassemblers, programming boards
- On-chip debug support via Device Access Port (DAP), Single-Pin DAP (SPD) or JTAG interface
- 64-pin Green LQFP package, 0.5 mm (19.7 mil) pitch

Ordering Information

The ordering code for an Infineon microcontroller provides an exact reference to a specific product. This ordering code identifies:

- the function set of the corresponding product type
- the temperature range[1]:
  - SAF-…: -40°C to 85°C
  - SAH-…: -40°C to 110°C
  - SAK-…: -40°C to 125°C
- the package and the type of delivery.

For ordering codes for the XC223[04]L please contact your sales representative or local distributor.

This document describes several derivatives of the XC223[04]L group:

Basic Device Types are readily available and
Special Device Types are only available on request.

1) Not all derivatives are offered in all temperature ranges.

Table 6 Pin Definitions and Functions (cont'd)

Pin	Symbol	Ctrl.	Type	Function
38	P2.10	O0 / I	St/B	**Bit 10 of Port 2, General Purpose Input/Output**
	U0C1_DOUT	O1	St/B	**USIC0 Channel 1 Shift Data Output**
	U0C0_SELO 3	O2	St/B	**USIC0 Channel 0 Select/Control 3 Output**
	CC2_CC23	O3 / I	St/B	**CAPCOM2 CC23IO Capture Inp./ Compare Out.**
	U0C1_DX0E	I	St/B	**USIC0 Channel 1 Shift Data Input**
	CAPINA	I	St/B	**GPT12E Register CAPREL Capture Input**
39	P2.11	O0 / I	St/B	**Bit 11 of Port 2, General Purpose Input/Output**
	U0C0_SELO 2	O1	St/B	**USIC0 Channel 0 Select/Control 2 Output**
	U0C1_SELO 2	O2	St/B	**USIC0 Channel 1 Select/Control 2 Output**
	U1C1_DX2A	I	St/B	**USIC1 Channel 1 Shift Control Input**
40	P2.12	O0 / I	St/B	**Bit 12 of Port 2, General Purpose Input/Output**
	U0C0_SELO 4	O1	St/B	**USIC0 Channel 0 Select/Control 4 Output**
	U0C1_SELO 3	O2	St/B	**USIC0 Channel 1 Select/Control 3 Output**
	U1C1_SCLK OUT	O3	St/B	**USIC1 Channel 1 Shift Clock Output**
	U1C1_DX1A	I	St/B	**USIC1 Channel 1 Shift Clock Input**
41,	P2.13	O0 / I	St/B	**Bit 13 of Port 2, General Purpose Input/Output**
	U1C1_DOUT	O1	St/B	**USIC1 Channel 1 Shift Data Output**
	CCU63_COU T60	O2	St/B	**CCU63 Channel 0 Output**
	U1C1_DX0B	I	St/B	**USIC1 Channel 1 Shift Data Input**
	U1C0_DX0B	I	St/B	**USIC1 Channel 0 Shift Data Input**

With its maximum resolution of 2 system clock cycles, the **GPT2 module** provides precise event control and time measurement. It includes two timers (T5, T6) and a capture/reload register (CAPREL). Both timers can be clocked with an input clock which is derived from the CPU clock via a programmable prescaler or with external signals. The counting direction (up/down) for each timer can be programmed by software or altered dynamically with an external signal on a port pin (TxEUD). Concatenation of the timers is supported with the output toggle latch (T6OTL) of timer T6, which changes its state on each timer overflow/underflow.

The state of this latch may be used to clock timer T5, and/or it may be output on pin T6OUT. The overflows/underflows of timer T6 can also be used to clock the CAPCOM2 timers and to initiate a reload from the CAPREL register.

The CAPREL register can capture the contents of timer T5 based on an external signal transition on the corresponding port pin (CAPIN); timer T5 may optionally be cleared after the capture procedure. This allows the XC223[04]L to measure absolute time differences or to perform pulse multiplication without software overhead.

The capture trigger (timer T5 to CAPREL) can also be generated upon transitions of GPT1 timer T3 inputs T3IN and/or T3EUD. This is especially advantageous when T3 operates in Incremental Interface Mode.

3.13 MultiCAN Module

The MultiCAN module contains two independently operating CAN nodes with Full-CAN functionality which are able to exchange Data and Remote Frames using a gateway function. Transmission and reception of CAN frames is handled in accordance with CAN specification V2.0 B (active). Each CAN node can receive and transmit standard frames with 11-bit identifiers as well as extended frames with 29-bit identifiers.

The two CAN nodes share a common set of message objects. Each message object can be individually allocated to either of the CAN nodes. Besides serving as a storage container for incoming and outgoing frames, message objects can be combined to build gateways between the CAN nodes or to set up a FIFO buffer.

The message objects are organized in double-chained linked lists, where each CAN node has its own list of message objects. A CAN node stores frames only into message objects that are allocated to its own message object list and it transmits only messages belonging to this message object list. A powerful, command-driven list controller performs all message object list operations.

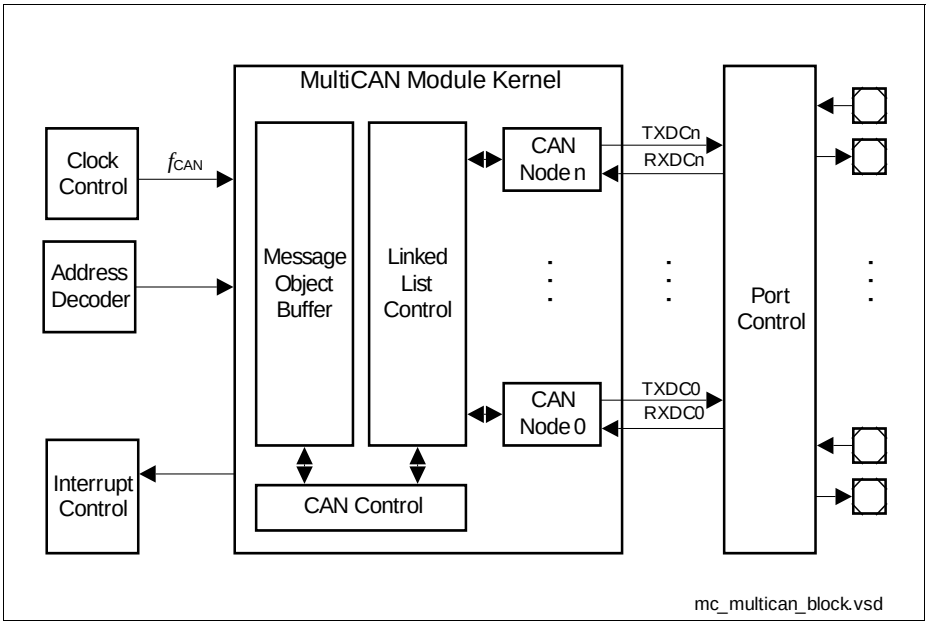

Figure 11 Block Diagram of MultiCAN Module

8) Value is controlled by on-chip regulator.

4.2 Voltage Range definitions

The XC223[04]L timing depends on the supply voltage. If such a dependency exists the timing values are given for 2 voltage areas commonly used. The voltage areas are defined in the following tables.

Table 14 Upper Voltage Range Definition

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Digital supply voltage for IO pads and voltage regulators	V_{DDP} SR	4.5	5.0	5.5	V	

Table 15 Lower Voltage Range Definition

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Digital supply voltage for IO pads and voltage regulators	V_{DDP} SR	3.0	3.3	4.5	V	

4.2.1 Parameter Interpretation

The parameters listed in the following include both the characteristics of the XC223[04]L and its demands on the system. To aid in correctly interpreting the parameters when evaluating them for a design, they are marked accordingly in the column “Symbol”:

CC (**C**ontroller **C**haracteristics):
The logic of the XC223[04]L provides signals with the specified characteristics.

SR (**S**ystem **R**equirement):
The external system must provide signals with the specified characteristics to the XC223[04]L.

4.3.2 DC Parameters for Lower Voltage Area

Keeping signal levels within the limits specified in this table ensures operation without overload conditions. For signal levels outside these specifications, also refer to the specification of the overload current I_{OV}.

Note: Operating Conditions apply.

Table 17 is valid under the following conditions: $V_{DDP} \geq$ 3.0 V; V_{DDP}typ. 3.3 V; $V_{DDP} \leq$ 4.5 V

Table 17 DC Characteristics for Lower Voltage Range

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Pin capacitance (digital inputs/outputs).	C_{IO} CC	–	–	10	pF	not subject to production test
Input Hysteresis[1)]	HYS CC	0.07 x V_{DDP}	–	–	V	R_S= 0 Ohm
Absolute input leakage current on pins of analog ports[2)]	$\|I_{OZ1}\|$ CC	–	10	200	nA	$V_{IN} > V_{SS}$; $V_{IN} < V_{DDP}$
Absolute input leakage current for all other pins. [2)3)]	$\|I_{OZ2}\|$ CC	–	0.2	2	µA	$T_J \leq$ 110 °C; $V_{IN} > V_{SS}$; $V_{IN} < V_{DDP}$
		–	0.2	6	µA	$T_J \leq$ 150 °C; $V_{IN} > V_{SS}$; $V_{IN} < V_{DDP}$
Pull Level Force Current[4)]	$\|I_{PLF}\|$ SR	150	–	–	µA	$V_{IN} \geq V_{IHmin}$ *(pulldown_enabled)*; $V_{IN} \leq V_{ILmax}$ *(pullup_enabled)* ;
Pull Level Keep Current[5)]	$\|I_{PLK}\|$ SR	–	–	10	µA	$V_{IN} \geq V_{IHmin}$ *(pullup_enabled);* $V_{IN} \leq V_{ILmax}$ *(pulldown_enabled)*

Table 17 DC Characteristics for Lower Voltage Range (cont'd)

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Input high voltage (all except XTAL1)	V_{IH} SR	0.7 x V_{DDP}	–	V_{DDP} + 0.3	V	
Input low voltage (all except XTAL1)	V_{IL} SR	-0.3	–	0.3 x V_{DDP}	V	
Output High voltage[6)]	V_{OH} CC	V_{DDP} - 1.0	–	–	V	$I_{OH} \geq I_{OHmax}$
		V_{DDP} - 0.4	–	–	V	$I_{OH} \geq I_{OHnom}$ [7)]
Output Low Voltage[6)]	V_{OL} CC	–	–	0.4	V	$I_{OL} \leq I_{OLnom}$ [8)]
		–	–	1.0	V	$I_{OL} \leq I_{OLmax}$

1) Not subject to production test - verified by design/characterization. Hysteresis is implemented to avoid metastable states and switching due to internal ground bounce. It cannot suppress switching due to external system noise under all conditions.

2) If the input voltage exceeds the respective supply voltage due to ground bouncing ($V_{IN} < V_{SS}$) or supply ripple ($V_{IN} > V_{DDP}$), a certain amount of current may flow through the protection diodes. This current adds to the leakage current. An additional error current (I_{INJ}) will flow if an overload current flows through an adjacent pin. Please refer to the definition of the overload coupling factor K_{OV}.

3) The given values are worst-case values. In production test, this leakage current is only tested at 125 °C; other values are ensured by correlation. For derating, please refer to the following descriptions: Leakage derating depending on temperature (T_J = junction temperature [°C]): I_{OZ} = 0.05 x $e^{(1.5 + 0.028 \times TJ>)}$ [µA]. For example, at a temperature of 95 °C the resulting leakage current is 3.2 µA. Leakage derating depending on voltage level (DV = V_{DDP} - V_{PIN} [V]): I_{OZ} = $I_{OZtempmax}$ - (1.6 x DV) (µA]. This voltage derating formula is an approximation which applies for maximum temperature.

4) Drive the indicated minimum current through this pin to change the default pin level driven by the enabled pull device.

5) Limit the current through this pin to the indicated value so that the enabled pull device can keep the default pin level.

6) The maximum deliverable output current of a port driver depends on the selected output driver mode. This specification is not valid for outputs which are switched to open drain mode. In this case the respective output will float and the voltage is determined by the external circuit.

7) As a rule, with decreasing output current the output levels approach the respective supply level (VOL->VSS, VOH->VDDP). However, only the levels for nominal output currents are verified.

8) As a rule, with decreasing output current the output levels approach the respective supply level (V_{OL}->V_{SS}, V_{OH}->V_{DDP}). However, only the levels for nominal output currents are verified.

4.3.3 Power Consumption

The power consumed by the XC223[04]L depends on several factors such as supply voltage, operating frequency, active circuits, and operating temperature. The power consumption specified here consists of two components:

- The switching current I_S depends on the device activity
- The leakage current I_{LK} depends on the device temperature

To determine the actual power consumption, always both components, switching current I_S and leakage current I_{LK} must be added:

$I_{DDP} = I_S + I_{LK}$.

Note: The power consumption values are not subject to production test. They are verified by design/characterization.
To determine the total power consumption for dimensioning the external power supply, also the pad driver currents must be considered.

The given power consumption parameters and their values refer to specific operating conditions:

- **Active mode**:
  Regular operation, i.e. peripherals are active, code execution out of Flash.
- **Stopover mode**:
  Crystal oscillator and PLL stopped, Flash switched off, clock in most parts of domain DMP_M stopped.

Note: The maximum values cover the complete specified operating range of all manufactured devices.
The typical values refer to average devices under typical conditions, such as nominal supply voltage, room temperature, application-oriented activity.
After a power reset, the decoupling capacitors for V_{DDIM} are charged with the maximum possible current.

For additional information, please refer to **Section 5.2**, **Thermal Considerations**.

Note: Operating Conditions apply.

Table 18 Switching Power Consumption

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Power supply current (active) with all peripherals active and EVVRs on	I_{SACT} CC	–	6 + 0.5 x f_{SYS} 1)	8 + 0.75 x f_{SYS} 1)	mA	power_mode= active ; voltage_range= both 2)3)4)
Power supply current in stopover mode, EVVRs on	I_{SSO} CC	–	0.7	2.0	mA	power_mode= stopover ; voltage_range= both

1) f_{SYS} in MHz

2) The pad supply voltage pins (V_{DDPB}) provide the input current for the on-chip EVVRs and the current consumed by the pin output drivers. A small current is consumed because the drivers input stages are switched.

3) Please consider the additional conditions described in section "Active Mode Power Supply Current".

4) The pad supply voltage only has a minor influence on this parameter.

Active Mode Power Supply Current

The actual power supply current in active mode not only depends on the system frequency but also on the configuration of the XC223[04]L's subsystem.

Besides the power consumed by the device logic the power supply pins also provide the current that flows through the pin output drivers.
A small current is consumed because the drivers' input stages are switched.

Table 23 A/D Converter Computation Table

GLOBCTR.5-0 (DIVA)	A/D Converter Analog Clock f_{ADCI}	INPCRx.7-0 (STC)	Sample Time[1] t_S
000000_B	f_{SYS}	00_H	$t_{ADCI} \times 2$
000001_B	f_{SYS} / 2	01_H	$t_{ADCI} \times 3$
000010_B	f_{SYS} / 3	02_H	$t_{ADCI} \times 4$
:	f_{SYS} / (DIVA+1)	:	$t_{ADCI} \times$ (STC+2)
111110_B	f_{SYS} / 63	FE_H	$t_{ADCI} \times 256$
111111_B	f_{SYS} / 64	FF_H	$t_{ADCI} \times 257$

1) The selected sample time is doubled if broken wire detection is active (due to the presampling phase).

Converter Timing Example A:

Assumptions: f_{SYS} = 80 MHz (i.e. t_{SYS} = 12.5 ns), DIVA = 03_H, STC = 00_H
Analog clock f_{ADCI} = f_{SYS} / 4 = 20 MHz, i.e. t_{ADCI} = 50 ns
Sample time t_S = $t_{ADCI} \times 2$ = 100 ns

Conversion 12-bit:

$t_{C12} = 16 \times t_{ADCI} + 2 \times t_{SYS} = 16 \times 50\text{ ns} + 2 \times 12.5\text{ ns} = 0.825\ \mu s$

Conversion 10-bit:

$t_{C10} = 12 \times t_{ADCI} + 2 \times t_{SYS} = 12 \times 50\text{ ns} + 2 \times 12.5\text{ ns} = 0.625\ \mu s$

Conversion 8-bit:

$t_{C8} = 10 \times t_{ADCI} + 2 \times t_{SYS} = 10 \times 50\text{ ns} + 2 \times 12.5\text{ ns} = 0.525\ \mu s$

Converter Timing Example B:

Assumptions: f_{SYS} = 66 MHz (i.e. t_{SYS} = 15.2 ns), DIVA = 03_H, STC = 00_H
Analog clock f_{ADCI} = f_{SYS} / 4 = 16.5 MHz, i.e. t_{ADCI} = 60.6 ns
Sample time t_S = $t_{ADCI} \times 2$ = 121.2 ns

Conversion 12-bit:

$t_{C12} = 16 \times t_{ADCI} + 2 \times t_{SYS} = 16 \times 60.6\text{ ns} + 2 \times 15.2\text{ ns} = 1.0\ \mu s$

Conversion 10-bit:

$t_{C10} = 12 \times t_{ADCI} + 2 \times t_{SYS} = 12 \times 60.6\text{ ns} + 2 \times 15.2\text{ ns} = 0.758\ \mu s$

4.6 Flash Memory Parameters

The XC223[04]L is delivered with all Flash sectors erased and with no protection installed.

The data retention time of the XC223[04]L's Flash memory (i.e. the time after which stored data can still be retrieved) depends on the number of times the Flash memory has been erased and programmed.

Note: These parameters are not subject to production test but verified by design and/or characterization.

Note: Operating Conditions apply.

Table 27 Flash Parameters

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Parallel Flash module program/erase limit depending on Flash read activity	N_{PP} SR	–	–	2[1)]		$N_{FL\_RD} \leq 1$
		–	–	1[2)]		$N_{FL\_RD} > 1$
Flash erase endurance for security pages	N_{SEC} SR	10	–	–	cycles	$t_{RET} \geq$ 20 years
Flash wait states[3)]	$N_{WSFLASH}$ SR	1	–	–		$f_{SYS} \leq$ 8 MHz
		2	–	–		$f_{SYS} \leq$ 13 MHz
		3	–	–		$f_{SYS} \leq$ 17 MHz
		4	–	–		$f_{SYS} >$ 17 MHz
Erase time per sector/page	t_{ER} CC	–	7[4)]	8.0	ms	
Programming time per page	t_{PR} CC	–	3[4)]	3.5	ms	
Data retention time	t_{RET} CC	20	–	–	years	$N_{ER} \leq$ 1,000 cycles
Drain disturb limit	N_{DD} SR	32	–	–	cycles	

Table 27 Flash Parameters (cont'd)

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Number of erase cycles	N_{ER} SR	–	–	15000	cycles	$t_{RET} \geq$ 5 years; Valid for up to 64 user selected sectors (data storage)
		–	–	1000	cycles	$t_{RET} \geq$ 20 years

1) All Flash module(s) can be erased/programmed while code is executed and/or data is read from only one Flash module or from PSRAM. The Flash module that delivers code/data can, of course, not be erased/programmed.
2) Flash module 1 can be erased/programmed while code is executed and/or data is read from Flash module 0.
3) Value of IMB_IMBCTRL.WSFLASH.
4) Programming and erase times depend on the internal Flash clock source. The control state machine needs a few system clock cycles. This increases the stated durations noticably only at extremely low system clock frequencies.

Access to the XC223[04]L Flash modules is controlled by the IMB. Built-in prefetch mechanisms optimize the performance for sequential access.

Flash access waitstates only affect non-sequential access. Due to prefetch mechanisms, the performance for sequential access (depending on the software structure) is only partially influenced by waitstates.

4.7.2 Definition of Internal Timing

The internal operation of the XC223[04]L is controlled by the internal system clock f_{SYS}.

Because the system clock signal f_{SYS} can be generated from a number of internal and external sources using different mechanisms, the duration of the system clock periods (TCSs) and their variation (as well as the derived external timing) depend on the mechanism used to generate f_{SYS}. This must be considered when calculating the timing for the XC223[04]L.

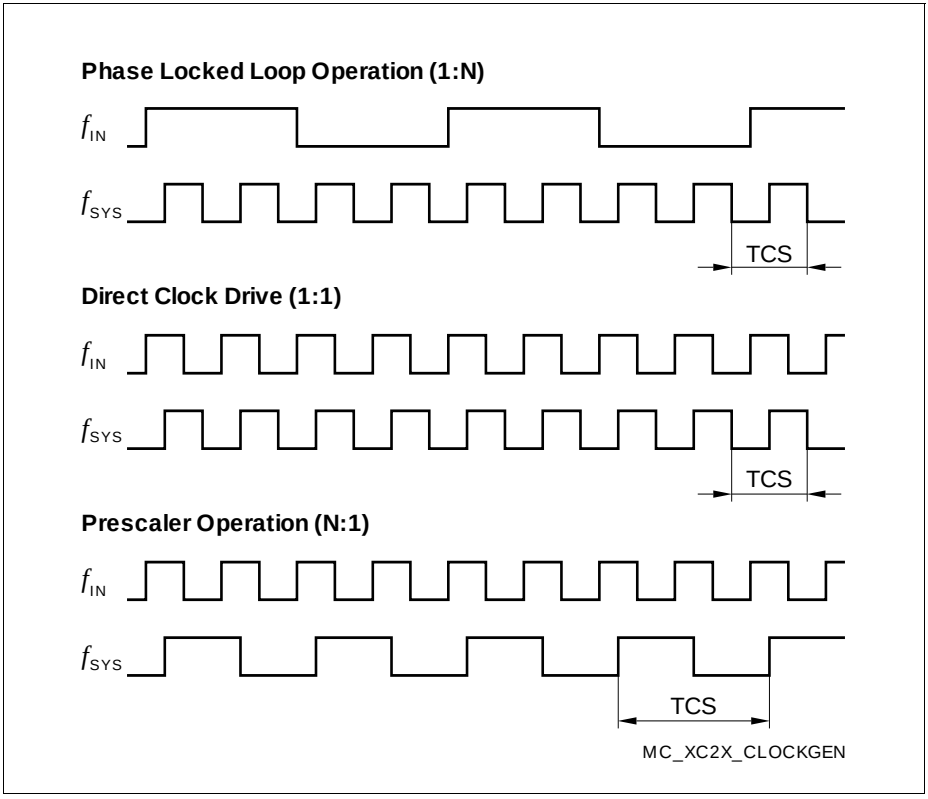

Figure 18 Generation Mechanisms for the System Clock

*Note: The example of PLL operation shown in **Figure 18** uses a PLL factor of 1:4; the example of prescaler operation uses a divider factor of 2:1.*

The specification of the external timing (AC Characteristics) depends on the period of the system clock (TCS).

The timing in the AC Characteristics refers to TCSs. Timing must be calculated using the minimum TCS possible under the given circumstances.
The actual minimum value for TCS depends on the jitter of the PLL. Because the PLL is constantly adjusting its output frequency to correspond to the input frequency (from crystal or oscillator), the accumulated jitter is limited. This means that the relative deviation for periods of more than one TCS is lower than for a single TCS (see formulas and **Figure 19**).

This is especially important for bus cycles using waitstates and for the operation of timers, serial interfaces, etc. For all slower operations and longer periods (e.g. pulse train generation or measurement, lower baudrates, etc.) the deviation caused by the PLL jitter is negligible.

The value of the accumulated PLL jitter depends on the number of consecutive VCO output cycles within the respective timeframe. The VCO output clock is divided by the output prescaler K2 to generate the system clock signal f_{SYS}. The number of VCO cycles is K2 × **T**, where **T** is the number of consecutive f_{SYS} cycles (TCS).

The maximum accumulated jitter (long-term jitter) D_{Tmax} is defined by:

D_{Tmax} [ns] = ±(220 / (K2 × f_{SYS}) + 4.3)

This maximum value is applicable, if either the number of clock cycles T > (f_{SYS} / 1.2) or the prescaler value K2 > 17.

In all other cases for a timeframe of **T** × TCS the accumulated jitter D_T is determined by:

D_T [ns] = D_{Tmax} × [(1 - 0.058 × K2) × (T - 1) / (0.83 × f_{SYS} - 1) + 0.058 × K2]

f_{SYS} in [MHz] in all formulas.

Example, for a period of 3 TCSs @ 33 MHz and K2 = 4:

D_{max} = ±(220 / (4 × 33) + 4.3) = 5.97 ns (Not applicable directly in this case!)

D_3 = 5.97 × [(1 - 0.058 × 4) × (3 - 1) / (0.83 × 33 - 1) + 0.058 × 4]
= 5.97 × [0.768 × 2 / 26.39 + 0.232]
= 1.7 ns

Example, for a period of 3 TCSs @ 33 MHz and K2 = 2:

D_{max} = ±(220 / (2 × 33) + 4.3) = 7.63 ns (Not applicable directly in this case!)

D_3 = 7.63 × [(1 - 0.058 × 2) × (3 - 1) / (0.83 × 33 - 1) + 0.058 × 2]
= 7.63 × [0.884 × 2 / 26.39 + 0.116]
= 1.4 ns

Table 30 Standard Pad Parameters for Upper Voltage Range (cont'd)

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Rise and Fall times (10% - 90%)	t_{RF} CC	–	–	38 + 0.6 x C_L	ns	$C_L \geq$ 20 pF; $C_L \leq$ 100 pF; Driver_Strength = Medium
		–	–	1 + 0.45 x C_L	ns	$C_L \geq$ 20 pF; $C_L \leq$ 100 pF; Driver_Strength = Strong ; Driver_Edge= Soft
		–	–	16 + 0.45 x C_L	ns	$C_L \geq$ 20 pF; $C_L \leq$ 100 pF; Driver_Strength = Strong ; Driver_Edge= Slow
		–	–	200 + 2.5 x C_L	ns	$C_L \geq$ 20 pF; $C_L \leq$ 100 pF; Driver_Strength = Weak

1) The total output current that may be drawn at a given time must be limited to protect the supply rails from damage. For any group of 16 neighboring output pins, the total output current in each direction (ΣI_{OL} and Σ-I_{OH}) must remain below 25 mA.

Table 31 Standard Pad Parameters for Lower Voltage Range

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Maximum output driver current (absolute value)[1)]	I_{Omax} CC	–	–	1.8	mA	Driver_Strength = Medium
		–	–	3.0	mA	Driver_Strength = Strong
		–	–	0.3	mA	Driver_Strength = Weak

4.7.5 Synchronous Serial Interface Timing

The following parameters are applicable for a USIC channel operated in SSC mode.

Note: These parameters are not subject to production test but verified by design and/or characterization.

Note: Operating Conditions apply.

Table 32 is valid under the following conditions: C_L= 20 pF; SSC= master ; voltage_range= upper

Table 32 USIC SSC Master Mode Timing for Upper Voltage Range

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Slave select output SELO active to first SCLKOUT transmit edge	t_1 CC	t_{SYS} - 8[1)]	–	–	ns	
Slave select output SELO inactive after last SCLKOUT receive edge	t_2 CC	t_{SYS} - 6[1)]	–	–	ns	
Data output DOUT valid time	t_3 CC	-6	–	9	ns	
Receive data input setup time to SCLKOUT receive edge	t_4 SR	31	–	–	ns	
Data input DX0 hold time from SCLKOUT receive edge	t_5 SR	-4	–	–	ns	

1) $t_{SYS} = 1 / f_{SYS}$

Table 33 is valid under the following conditions: C_L= 20 pF; *SSC*= master ; voltage_range= lower

Table 33 USIC SSC Master Mode Timing for Lower Voltage Range

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Slave select output SELO active to first SCLKOUT transmit edge	t_1 CC	t_{SYS} - 10[1)]	–	–	ns	
Slave select output SELO inactive after last SCLKOUT receive edge	t_2 CC	t_{SYS} - 9[1)]	–	–	ns	
Data output DOUT valid time	t_3 CC	-7	–	11	ns	
Receive data input setup time to SCLKOUT receive edge	t_4 SR	40	–	–	ns	
Data input DX0 hold time from SCLKOUT receive edge	t_5 SR	-5	–	–	ns	

1) $t_{SYS} = 1 / f_{SYS}$

Table 34 is valid under the following conditions: C_L= 20 pF; *SSC*= slave ; voltage_range= upper

Table 34 USIC SSC Slave Mode Timing for Upper Voltage Range

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Select input DX2 setup to first clock input DX1 transmit edge[1)]	t_{10} SR	10	–	–	ns	
Select input DX2 hold after last clock input DX1 receive edge[1)]	t_{11} SR	7	–	–	ns	
Receive data input setup time to shift clock receive edge[1)]	t_{12} SR	7	–	–	ns	

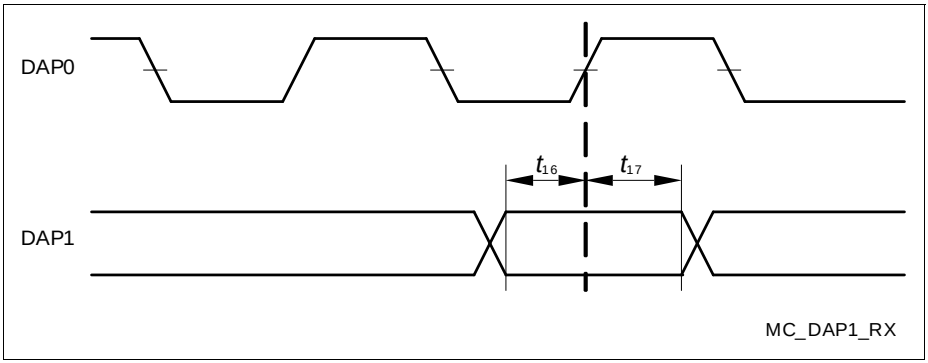

Figure 23 DAP Timing Host to Device

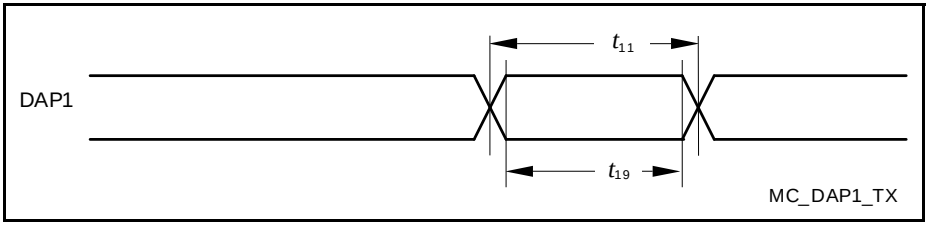

Figure 24 DAP Timing Device to Host

Note: The transmission timing is determined by the receiving debugger by evaluating the sync-request synchronization pattern telegram.

particular, the size of the Exposed Pad (if present) may vary.

If different device types are considered or planned for an application, it must be ensured that the board layout fits all packages under consideration.

Package Outlines

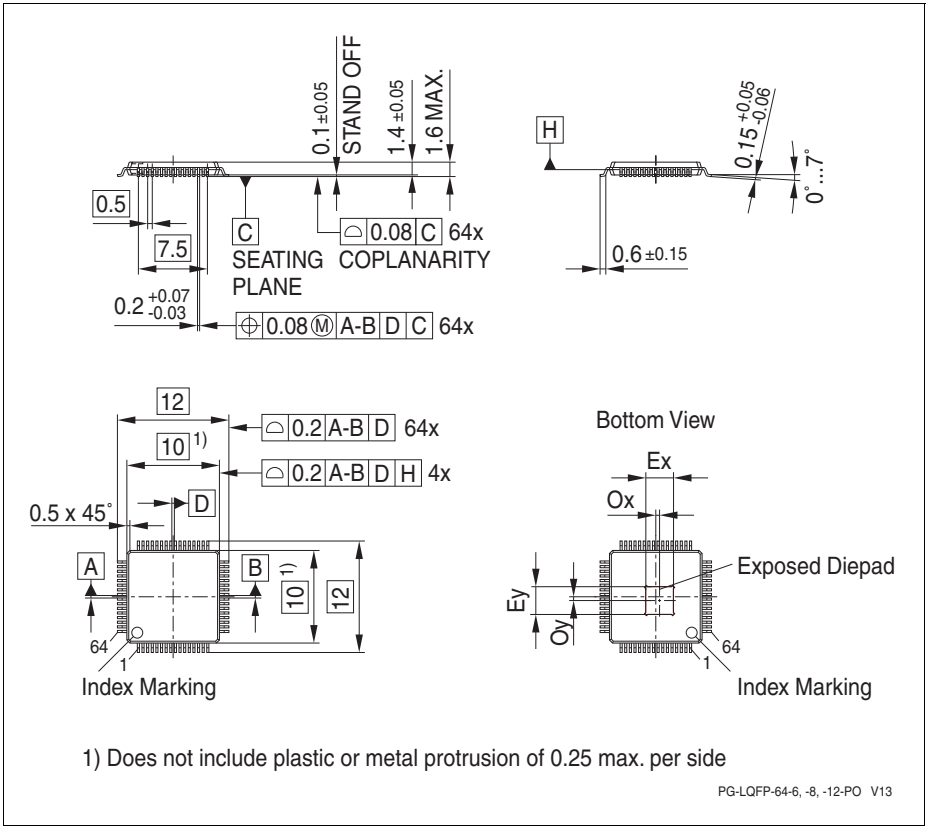

Figure 27 PG-LQFP-64-22/-24 (Plastic Green Thin Quad Flat Package)

All dimensions in mm.

You can find complete information about Infineon packages, packing and marking in our Infineon Internet Page “Packages”: **http://www.infineon.com/packages**